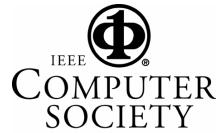

Proceedings

Sixth European Dependable Computing Conference

EDCC 2006

**18-20 October 2006
Coimbra, Portugal**



Los Alamitos, California
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IEEE Computer Society Order Number P2648

ISBN 0-7695-2648-9

ISBN-13 978-0-7695-2648-5

Library of Congress 2006928184

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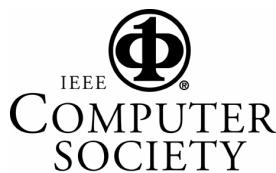
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Individual paper REPRINTS may be ordered at: reprints@computer.org

Editorial production by Silvia Ceballos

Cover art production by Joseph Daigle

Printed in the United States of America by Applied Digital Imaging



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Sixth European Dependable Computing Conference

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